



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**Prosemi Pte Ltd**  
3 Tai Seng Drive, #04-01  
Singapore 535216

Fulfills the requirements of

**ISO/IEC 17025:2017**

and

**AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program**

In the field of

**TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

Jason Stine, Vice President

Expiry Date: 21 September 2025

Certificate Number: AT-3240



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

**Prosemi Pte Ltd**  
 3 Tai Seng Drive, #04-01  
 Singapore 535216  
 Lee Sheng Chuan +65-63115374  
[sclee@fusionww.com](mailto:sclee@fusionww.com)

**TESTING**

Valid to: **September 21, 2025**

Certificate Number: **AT-3240**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **Prosemi Pte Ltd** to perform the following AS6171 slash sheet tests:

**Non-Destructive Testing**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	IDEA-STD-1010 SAE AS6081, 4.2.6.4.2.2 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
XRF	IDEA-STD-1010 SAE AS6081, 4.2.6.4.5 SAE AS6171/3	Electrical, Electronic and Electromechanical (EEE) Components	Fisherscope X-Ray Machine (XRF) (Model: XDAL 237 SDD)
X-ray	IDEA-STD-1010 SAE AS6081, 4.2.6.4.4 SAE AS6171/5	Electronic and Electromechanical (EEE) Components	SEAMARK X5600 X-Ray Machine, CE X-Ray Machine

**Mechanical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Remarking - Permanency	IDEA-STD-1010 SAE AS6081, 4.2.6.4.3A SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Resurfacing - Acetone	IDEA-STD-1010 SAE AS6081, 4.2.6.4.3B.1 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Resurfacing - 1-Methyl 2-Pyrrolidinone	IDEA-STD-1010 SAE AS6081, 4.2.6.4.3B.2 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Resurfacing - Dynasolve	IDEA-STD-1010 SAE AS6081, 4.2.6.4.3B.3 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Scrape Test	IDEA-STD-1010 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Dimensional Measurement	IDEA-STD-1010-B, 10.3.3 SAE AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Digital Caliper
Solderability Test	MIL-STD-883 METHOD 2003.12 ANSI/J-STD-002	Electrical, Electronic and Electromechanical (EEE) Components	Hentec Pulsar Solderability Tester, Microscope
Cross Section	SAE AS6171/3 SAE AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Metkon Forcipol 102
Delid/Decapsulation Internal Analysis	SAE AS6081 4.2.6.4.6 SAE AS6171/4	Electrical, Electronic and Electromechanical (EEE) Components	Nisene JetEtch Pro JEP1000, Microscope

**Electrical**

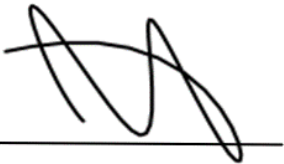
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
LCR (Inductor, Capacitor, Resistor)	MIL-STD-202 SAE AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	Agilent Precision, LCR Meter
Curve Tracer	MIL-STD-750E METHOD: 4011, 4016, 4022	Electrical, Electronic and Electromechanical (EEE) Components	Digilent System

**Electrical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Functional	MIL-STD-883 METHOD 3014	Electrical, Electronic and Electromechanical (EEE) Components	DC Power Supply, Multimeter, Oscilloscope, Function Generator

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-3240.



Jason Stine, Vice President

